

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**
(Not for submission under 37 CFR 1.99)

Application Number	10781985
Filing Date	2004-02-20
First Named Inventor	Uri MAHLAB
Art Unit	2613
Examiner Name	David S. KIM
Attorney Docket Number	MAHLAB-8

/DSK/	12	Fiber Optic Test and Measurement, Derickson, Dennis. Book, 1998, Prentice Hall, USA ., Section 1.12.5	<input type="checkbox"/>
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Examiner Signature	/David S. Kim/	Date Considered	12/18/2007
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Application Number	10/781,985
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Group Art Unit	4645 2613
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/DSK/	AL	G. Rossi et al. "Optical Performance Monitoring in Reconfigurable WDM Optical Networks Using Subcarrier Multiplexing", Journal of Lightwave Technology, Vol. 18, No. 12, December 2000.	
	AM	A. Sano et al. "Adaptive Dispersion Equalization by Monitoring Relative Phase Shift Between Spacing-Fixed WDM Signals", Journal of Lightwave Technology, Vol. 19 No. 3, March 2001.	
	AN	A. E. Willner et al. "Tunable Compensation of Channel Degrading Effects Using Nonlinearly Chirped Passive Fiber Bragg Gratings", IEEE Journal of Selected Topics in Quantum Electronics, Vol. 5, No. 5, September/October 1999.	
↓	AO	S. Wielandy et al. "Real-time measurement of accumulated chromatic dispersion for automatic dispersion compensation", Electronic Letters, Vol. 38, No. 20, September, 26, 2002.	

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U.S.PATENTS

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/DSK/	1	20010001620	KR		2001-01-05	Kim Sang Ho et al.	Abstract only	<input type="checkbox"/>

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/DSK/	1	Simple Measurement Of Fiber Dispersion And Of Chirp Parameter Of Intensity Modulated Light Emitter. F. Devaux, Y. Sorel And J.F.Kerdiles. Journal of Lightwave Technology, Vol.11, No.12 December 1993.	<input type="checkbox"/>
	2	Direct Measurement Of Chirped Fundamental And Stimulated Raman Radiation In Fibers. Gomes, A. S. L. (Imperial Coll, London, Engl); Da Silva, V. L.; Taylor, J. R., Optical Soc of America, 1987, p 82	<input type="checkbox"/>
	3	Variation of frequency chirp with wavelength in an InGaAsP/InP multiple-quantum-well (MQW) waveguide electroabsorption modulator, M.S. Whalen; T.H. Wood; B.I. Miller; U. Koren; C.A. Burrus; G. Raybon, Photonics Technology Letters, IEEE, Volume: 3. Issue: 5 May 1991, Page(s): 451-452	<input type="checkbox"/>
	4	Wideband chirp measurement technique for high bit rate sources. R.A. Sanders, J.P. King, and I. Hardcastle. IEEE 1994. Electronics Letters Online No:19940917, 20 June 1994.	<input type="checkbox"/>
	5	Time-resolved measurement of dynamic frequency chirp due to electrostriction mechanism in optical fibers, D. Le Quang; Y. Jaouen; M. Zimmerli; P. Gallion; J.B. Thomine, Photonics Technology Letters, IEEE, Volume: 8 Issue: 3 March 1996, Page(s): 414-416	<input type="checkbox"/>
	6	Time-resolved frequency chirp measurement using a silicon-wafer etalon, S. Tammela; H. Ludvigsen; T. Kajava; M. Kaivola, Photonics Technology Letters, IEEE, Volume: 9 Issue: 4 April 1997, Page(s): 475-477	<input type="checkbox"/>
	7	http://lib.tkk.fi/Diss/2002/isbn9512259869/isbn9512259869.pdf - Dispersion measurements of fiber-optic components and applications of a novel tunable filter for optical communications. Tapio Niemi. Helsinki University of Technology. Department of ECE. June 14, 2002.	<input type="checkbox"/>
	8	"Device for frequency chirp measurements of optical transmitters in real time" Tapio Niemi et al .Review of scientific instruments, Vol 73, no.3; March 2002	<input type="checkbox"/>
	9	Chirp Measurement of Multimode Q-Switched Laser Diode Pulses by Use of a Streak Camera and a Grating Monochromator, A. Bresson, N. Stelmakh, J. -M. Lourtioz, A. Shen, and C. Froehly, Appl. Opt. 37, 1022-1025 (1998)	<input type="checkbox"/>
	10	https://www.cerias.purdue.edu/tools_and_resources/bibtex_archive/archive/2000-26.pdf DIRECT SPACE-TO-TIME PULSE SHAPING FOR ULTRAFast OPTICAL WAVEFORM GENERATION. - Daniel Leaird. A thesis submitted to the Faculty of Purdue University. December 2000	<input type="checkbox"/>
↓	11	http://www.tek.com/Masurement/cgi-bin/framed.pl?Document=/Measurement/Products/press/optical/&FrameSet=optical - Tektronix Makes Strong Push into DWDM Market with Portfolio of Photonics Network Measurement Systems - Q7606 Chirp Test Instrument.	<input type="checkbox"/>